

**1997 21st INTERNATIONAL CONFERENCE
ON MICROELECTRONICS**

PROCEEDINGS



Niš, Yugoslavia
14-17 September 1997

Volume 2

organized by
Yugoslavia IEEE Section - Electron Devices Chapter

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Published by the
ELECTRON DEVICES SOCIETY
of the
INSTITUTE OF ELECTRICAL AND ELECTRONICS ENGINEERS, INC.

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IEEE Catalog Number 97TH8232
ISBN 0-7803-3664-X (softbound)
ISBN 0-7803-3665-8 (microfiche)
Library of Congress Number 96-78106

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